



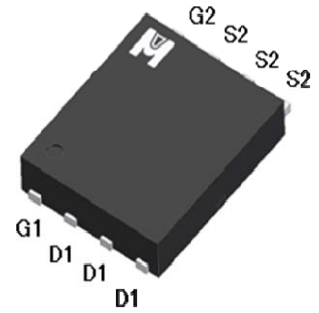
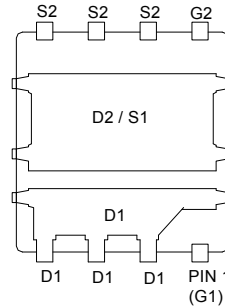
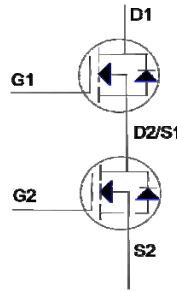
**N-Channel Logic Level Enhancement Mode Field Effect Transistor**

Product Summary:

	N-CH-Q1	N-CH-Q2
BV <sub>DSS</sub>	30V	30V
R <sub>DS(on) (MAX.)</sub>	7mΩ	3.5mΩ
I <sub>D</sub>	15A	25A

UIS, R<sub>g</sub> 100% Tested

Pb-Free Lead Plating & Halogen Free



**ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNIT
			Q1	Q2	
Gate-Source Voltage		V <sub>GS</sub>	±20	±20	V
Continuous Drain Current	T <sub>C</sub> = 25 °C	I <sub>D</sub>	15	25	A
	T <sub>C</sub> = 100 °C		12	18	
Pulsed Drain Current <sup>1</sup>		I <sub>DM</sub>	60	100	
Avalanche Current		I <sub>AS</sub>	15	25	
Avalanche Energy	L = 0.1mH, R <sub>G</sub> =25 Ω	E <sub>AS</sub>	11.25	31.25	mJ
Repetitive Avalanche Energy <sup>2</sup>	L = 0.05mH	E <sub>AR</sub>	5.62	15.62	
Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	48	100	W
	T <sub>C</sub> = 100 °C		19	40	
Operating Junction & Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150		°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL		TYPICAL	MAXIMUM		UNIT
	R <sub>θJC</sub>	Steady State		2.6	1.25	
Junction-to-Case	R <sub>θJC</sub>	Steady State		2.6	1.25	°C / W
Junction-to-Ambient	R <sub>θJA</sub>	Steady State		62	55	
	R <sub>θJA</sub>	t ≤ 10 s		27	24	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

R<sub>θJA</sub> when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



ELECTRICAL CHARACTERISTICS (T<sub>c</sub> = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT	
			MIN	TYP	MAX		
<b>STATIC</b>							
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	Q1	30		V	
			Q2	30			
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	Q1	1	1.5	3	
			Q2	1	1.5	3	
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	Q1			±100	nA
			Q2			±100	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V	Q1			1	μA
			Q2			1	
		V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125 °C	Q1			25	
			Q2			25	
On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V	Q1	15			A
			Q2	25			
Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 12A	Q1		5.5	7	mΩ
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	Q2		2.5	3.5	
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 9A	Q1		7	9.5	
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 15A	Q2		3.5	4.7	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 13A	Q1		50		S
		V <sub>DS</sub> = 5V, I <sub>D</sub> = 20A	Q2		95		
<b>DYNAMIC</b>							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz	Q1		975		pF
			Q2		2200		
Output Capacitance	C <sub>oss</sub>		Q1		168		
			Q2		427		
Reverse Transfer Capacitance	C <sub>rss</sub>		Q1		95		
			Q2		231		
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> = 15mV, V <sub>DS</sub> = 0V, f = 1MHz	Q1		2.5		Ω
			Q2		2.5		
Total Gate Charge <sup>1,2</sup>	Q <sub>g</sub> (V <sub>GS</sub> =10V)	V <sub>DD</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 10A	Q1		17		nC
			Q2		32		
	Q <sub>g</sub> (V <sub>GS</sub> =4.5V)		Q1		8.7		
			Q2		17		



Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$	$V_{DD} = 15V, V_{GS} = 10V,$ $I_D = 10A$	Q1		3		
			Q2		4.1		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$		Q1		2.8		
			Q2		8.5		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(on)}$	$V_{DD} = 15V,$ $I_D = 1A, V_{GS} = 10V, R_{GS} = 2.7\Omega$	Q1		8		nS
Rise Time <sup>1,2</sup>	$t_r$		Q2		15		
			Q1		10		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(off)}$		Q2		10		
			Q1		20		
Fall Time <sup>1,2</sup>	$t_f$		Q2		50		
		Q1		15			
			Q2		15		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_C = 25\text{ }^\circ\text{C}</math>)</b>							
Continuous Current	$I_S$		Q1			15	A
			Q2			25	
Pulsed Current <sup>3</sup>	$I_{SM}$		Q1			60	
			Q2			100	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 10A, V_{GS} = 0V$	Q1			1.2	V
			Q2			1.2	
Reverse Recovery Time	$t_{rr}$	Q1		20		nS	
Reverse Recovery Charge	$Q_{rr}$	Q2					nC
			Q1		11		
			Q2		10		

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

<sup>3</sup>Pulse width limited by maximum junction temperature.



杰力科技股份有限公司

*Excelliance MOS Corporation* (Preliminary)

EMB03K03HP

**Ordering & Marking Information:**

Device Name: EMB03K03HP for Asymmetric Dual EDFN 5 x 6

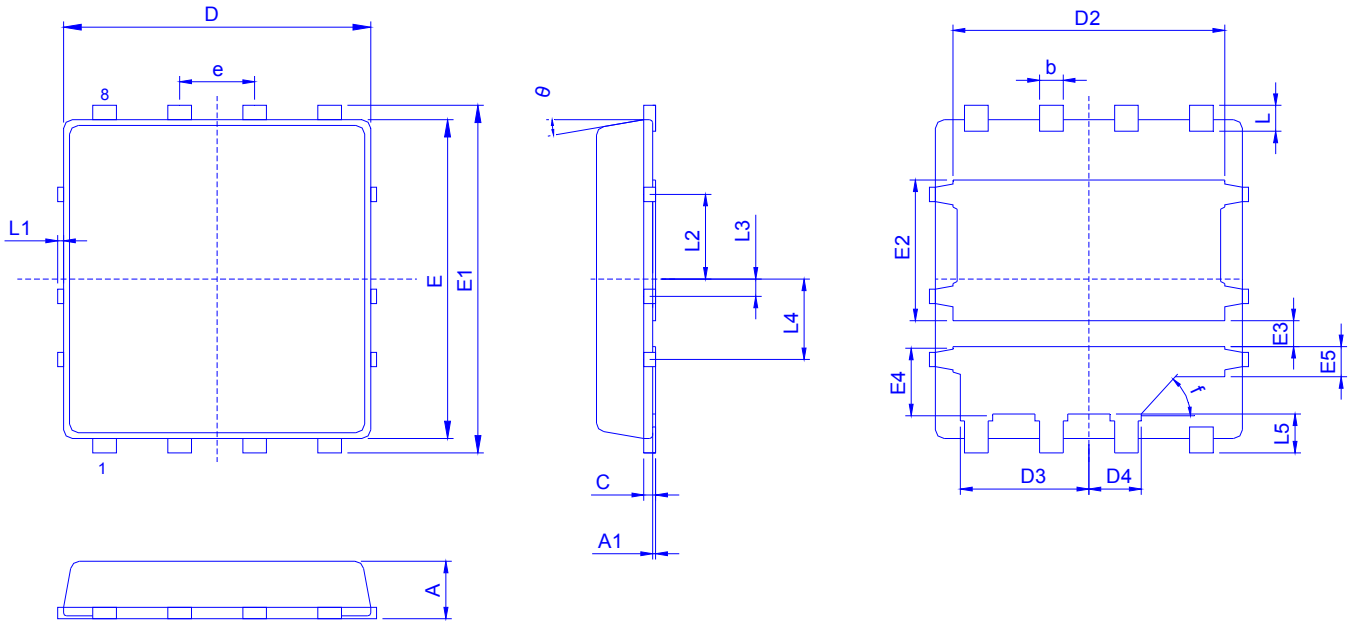


→ B03K03: Device Name

→ ABCDEFG: Date Code



Outline Drawing



Dimension in mm

Dimension	A	A1	b	c	D	D2	D3	D4	E	E1	E2	E3	E4	E5
Min.	0.85	0.00	0.35	0.15		4.5	2.125	0.835			2.4	0.40	1.125	0.475
Typ.	0.90		0.40	0.20	5.2	4.6	2.175	0.885	5.55	6.05	2.45	0.45	1.175	0.525
Max.	1.00	0.05	0.45	0.25		4.7	2.225	0.935			2.5	0.50	1.225	0.575

Dimension	e	L	L1	L2	L3	L4	L5	F	θ
Min.		0.35	0	1.375	0.2	1.3	0.575		0°
Typ.	1.27	0.45		1.475	0.3	1.4	0.675	45°	
Max.		0.55	0.1	1.575	0.4	1.5	0.775		10°

Recommended minimum pads

